

Model 4121B

Gated Integrator



SIGNAL RECOVERY

FEATURES

- ◆ 1 ns minimum gate width
- ◆ 80 kHz max trigger rate
- ◆ Linear or Exponential averaging
- ◆ Input offset control
- ◆ Normal and Baseline sampling modes
- ◆ Built-in trigger generator

APPLICATIONS

- ◆ Pulsed laser experiments
- ◆ Phosphorescence decay time studies
- ◆ Precision signal sampling

DESCRIPTION

This module is an ideal component for building boxcar averager systems. It includes a wide bandwidth variable gain AC/DC coupled input amplifier with offset adjustment and a high speed sampling gate with variable width and delay controls. It operates in normal or baseline sampling mode and features a switch-selected choice of how many samples are included in the averaging process. Separate outputs for the average and last sample taken are also provided. A gate monitor supplies a synchronized gate output pulse for application to an oscilloscope trigger or for referencing associated processing electronics. Trigger input is ECL or TTL or can be derived from the module's own adjustable trigger generator.

The module is packaged in a 2-unit wide NIM format and as such requires a suitable NIM rack and power supply to operate. The simplest single-channel system can therefore be produced with one model 4121B module and a suitable NIM rack and power supply (such as the **SIGNAL RECOVERY** model 4006 or 4001A/4002D). The addition of a second model 4121B and a model 4161A Display/ADC and control module provides a dual channel system with the added capability of allowing the transfer of output data to a computer for external analysis. Further modules can be added to increase the overall number of channels.

The unit can also be used with other **SIGNAL RECOVERY** instruments, such as our lock-in amplifiers, to build systems capable of swept-gate waveform recovery experiments, all controlled via the Acquire data acquisition software.

Specifications

General

Single-channel gated integrator module mounted in NIM enclosure with adjustable sensitivity, offset, gatewidth and output averager. Manual controls.

Analog gate delay generator with manual or DC voltage control.

Measurement Modes

On receipt of an external trigger, the instrument waits for the preset gate delay and then integrates the voltage present at its input for the preset gate width. On completion a DC voltage representing this integral is provided at the Last Sample Output connector and in addition fed forward into an analog integrator stage.

Signal Channel

Mode Normal or Baseline Sampling

Sensitivity	± 20 mV to ± 2 V in 1-2-5 sequence
Coupling	AC/DC
Impedance	
DC only	50 Ω // 10 pF
DC or AC	1 M Ω // 30 pF
Maximum Safe Input	
50 Ω Input	± 5 V
1 M Ω Input	± 100 V
Offset	$\pm 10 \times$ FS; non-removable
Overload Indicator	LED
Overload Level	Input (signal plus noise) $> 1.1 \times$ FS
Overload Recovery	Recovers after 1 sample for $\times 10$ overload
Gain Drift	0.5% / $^{\circ}$ C, gate width > 30 ns; 1.0% / $^{\circ}$ C, gate width < 10 ns

DC Drift (referred to input)	0.2%/°C, gate width > 20 ns; 1.0%/°C, gate width < 20 ns	Trigger Source Internal	0.5 Hz to 40 kHz selectable with range switches 0.5, 5, 50, 500, 5000, off. Vernier is 10× range.	LSO Droop Rate Averager Droop Rate	< 0.2% FS/s When there are no triggers the droop rate is < 0.001% per minute for 10k samples
Bandwidth		External ECL	Positive edge, 5 ns min pulse width with termination of 50 Ω to -2 V; -5 V to +10 V pk-pk safe input.	Outputs Average Out	±10 V FS with 50 Ω output impedance and capable of driving 2 kΩ load
Signal Risetime		TTL	Negative edge, 20 ns min pulse width; -5 V to +10 V safe input.	Last Sample Out Gate Monitor	±10 V FS 0.3 V into 50 Ω to ground. Marker pulse-width equals gate width. Position is within 5 ns from actual gate
Sampler and Timing		Max. Trigger Rate	80 kHz	Trigger Baseline Output	TTL TTL output line that toggles with each trigger to indicate whether next sample is signal or baseline value.
Gate Width	1 ns to 30 μs in 1-3-10 sequence, switch selectable with a continuously variable ×1 to ×5 multiplier	Trigger Indicator	LED lights when unit is triggered		
Sample Correlation	Less than 0.5% of the sample output due to trigger <i>t</i> remains at trigger <i>t</i> + 1	Trigger Generator Output	BNC TTL out on rear panel active in all trigger modes. Polarity set by jumper.	General Power Requirements	+24 V at 200 mA; -24 V at 150 mA; +12 V at 300 mA; -12 V at 590 mA; +6 V at 160 mA; -6 V at 630 mA
Gate Delay		Frequency ranges	0.5, 5, 50, 500 Hz, 5 kHz and off with vernier to overlap ranges.		
Input	0 to 10 V DC varies delay by 0.5% to 100% of range setting	Baseline Input	TTL line to indicate whether sample is signal or baseline value.	Dimensions	
Max delay	3 ns to 300 ns in a 1-3-10 sequence plus user options, which give 10 μs (default), and 1 μs, 100 μs, 1 ms or 3 ms by capacitor change.	Analog Output Averager		Height	8¾" (222 mm)
		Mode	Linear or Exponential	Width	2¾" (70 mm)
		Samples Averaged	1, 3, 10, 30, 100, 300, 1k, 10k	Depth	9¾" (248 mm)
				Weight	3 lb (1.4 kg)

Why should you choose **SIGNAL RECOVERY** products?

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SIGNAL RECOVERY Product Features

SIGNAL RECOVERY Product Features	Benefit to you
◆ Higher maximum sensitivity	Sensitivity settings on 4121B are for a full 10 V output, not the 1 V of competing units, allowing you to measure smaller signals
◆ High input bandwidth	Signals are less distorted before being sampled
◆ 1 ns minimum gate width	Isolate narrower features more easily. In scanned gate work obtain finer resolution of peaks
◆ Built-in trigger generator	Use to trigger your experiment
◆ Linear or exponential averaging	Linear averaging means that every sample contributes equally to the output
◆ Baseline Out output	Will directly drive one of our light choppers for automatic baseline subtraction
◆ Faster Triggering	80 kHz max trigger rate allows acquisition up to 4 times faster than competing instruments
◆ Excellent reset of integrator between triggers	Ensures that each sample is essentially independent of previous samples